



General Multilayer Ceramic Capacitors



MLCC is an electronic part that temporarily stores an electrical charge and the most prevalent type of capacitor today. New technologies have enabled the MLCC manufacturers to follow the trend dictated by smaller and smaller electronic devices such as Cellular telephones, Computers, DSC, DVC

General Features

- Miniature Size
- Wide Capacitance and Voltage Range
- Tape & Reel for Surface Mount Assembly
- Low ESR

Applications

- General Electronic Circuit

Part Numbering

<u>CL</u>	<u> 10</u>	<u>B</u>	<u> 104</u>	K	<u>B</u>	<u>8</u>	N	N	N	<u>C</u>

Samsung Multilayer Ceramic Capacitor

Size(mm)

Capacitance Temperature Characteristic

Nominal Capacitance

Capacitance Tolerance

Rated Voltage

Thickness Option

Product & Plating Method

Samsung Control Code

Reserved For Future Use

Packaging Type

Samsung Multilayer Ceramic Capacitor

SIZE(mm)

Code	EIA CODE	Size(mm)
03	0201	0.6 × 0.3
05	0402	1.0 × 0.5
10	0603	1.6 × 0.8
21	0805	2.0 × 1.25
31	1206	3.2 × 1.6
32	1210	3.2 × 2.5
43	1812	4.5 × 3.2
55	2220	5.7 × 5.0





CAPACITANCE TEMPERATURE CHARACTERISTIC

Code		Temperature Range			
С		COG	С	0 ± 30(ppm/)	
Р		P2H	Р	-150 ± 60	
R		R2H	R	-220 ± 60	
S	Class	S2H	S	-330 ± 60	-55 ~ +125
Т		T2H	Т	-470 ± 60	
U		U2J	U	-750 ± 60	
L		S2L	S	+350 ~ -1000	
Α		X5R	X5R	± 15%	-55 ~ +85
В	Class	X7R	X7R	± 15%	-55 ~ +125
X	Class	X6S	X6S	± 22%	-55 ~ +105
F		Y5V	Y5V	+22 ~ -82%	-30 ~ +85

Temperature Characteristic

Temperature Characteristics	Below 2.0pF	2.2 ~ 3.9pF	Above 4.0pF	Above 10pF
С	C0G	C0G	C0G	C0G
Р	-	P2J	P2H	P2H
R	-	R2J	R2H	R2H
S	-	S2J	S2H	S2H
Т	-	T2J	T2H	T2H
U	-	U2J	U2J	U2J

 $J: \pm 120PPM/$, $H: \pm 60PPM/$, $G: \pm 30PPM/$

NOMINAL CAPACITANCE

Nominal capacitance is identified by 3 digits.

The first and second digits identify the first and second significant figures of the capacitance.

The third digit identifies the multiplier. 'R' identifies a decimal point.

Example

Code	Nominal Capacitance
1R5	1.5pF
103	10,000pF, 10nF, 0.01 μF
104	100,000pF, 100nF, 0.1 μ F





CAPACITANCE TOLERANCE

Code	Tolerance	Nominal Capacitance
Α	±0.05pF	
В	± 0.1pF	
С	± 0.25pF	Less than 10pF (Including 10pF)
D	± 0.5pF	(meldaling Topi)
F	±1pF	
F	±1%	
G	±2%	
J	±5%	More than 10pF
K	± 10%	More than 10pF
М	±20%	
Z	+80, -20%	

RATED VOLTAGE

Code	Rated Voltage	Code	Rated Voltage
R	4.0V	D	200 V
Q	6.3V	E	250V
P	10V	G	500 V
O	16V	Н	630 V
Α	25V	I	1,000V
L	35V	J	2,000V
В	50V	К	3,000V
С	100V		





THICKNESS OPTION

Size	Code	Thickness(T)	Size	Code	Thickness(T)
0201(0603)	3	0.30±0.03		F	1.25 ± 0.20
0402(1005)	5	0.50±0.05		Н	1.6±0.20
0603(1608)	8	0.80±0.10	1812(4532)	ı	2.0±0.20
	Α	0.65±0.10		J	2.5±0.20
0005(2042)	С	0.85±0.10		L	3.2±0.30
0805(2012)	F	1.25±0.10		F	1.25 ± 0.20
	Q	1.25±0.15		Н	1.6±0.20
	С	0.85±0.15	2220(5750) I		2.0±0.20
1206(3216)	F	1.25±0.15		J	2.5±0.20
	Н	1.6 ± 0.20		L	3.2±0.30
	F	1.25±0.20			
	Н	1.6 ± 0.20			
1210(3225)	ı	2.0 ± 0.20			
	J	2.5 ± 0.20			
	V	2.5 ± 0.30			

PRODUCT & PLATING METHOD

Code	Electrode	Termination	Plating Type
Α	Pd	Ag	Sn_100%
N	Ni	Cu	Sn_100%
G	Cu	Cu	Sn_100%

SAMSUNG CONTROL CODE

Code	Description of the code	Code	Description of the code
Α	Array (2-element)	N	Normal
В	Array (4-element)	Р	Automotive
С	High - Q	L	LICC





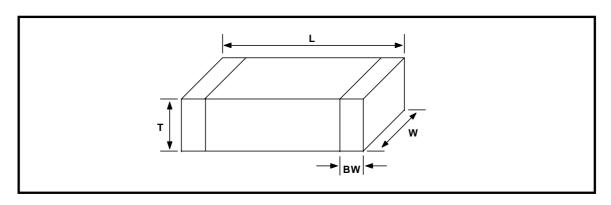
RESERVED FOR FUTURE USE

Code	Description of the code
N	Reserved for future use

PACKAGING TYPE

Code	Packaging Type	Code	Packaging Type
В	Bulk	F	Embossing 13" (10,000EA)
Р	Bulk Case	L	Paper 13" (15,000EA)
С	Paper 7"	О	Paper 10"
D	Paper 13" (10,000EA)	S	Embossing 10"
Е	Embossing 7"		

APPEARANCE AND DIMENSION



CODE	EIA CODE	DIMENSION (mm)								
CODE	EIA CODE	L	w	T (MAX)	BW					
03	0201	0.6 ± 0.03	0.3 ± 0.03	0.33	0.15 ± 0.05					
05	0402	1.0 ± 0.05	0.5 ± 0.05	0.55	0.2 +0.15/-0.1					
10	0603	1.6 ± 0.1	0.8 ± 0.1	0.9	0.3 ± 0.2					
21	0805	2.0 ± 0.1	1.25 ± 0.1	1.35	0.5 +0.2/-0.3					
24	1206	3.2 ± 0.15	1.6 ± 0.15	1.40	0.5 +0.2/-0.3					
31		3.2 ± 0.2	1.6 ± 0.2	1.8	0.5 +0.3/-0.3					
32	1210	3.2 ± 0.3	2.5 ± 0.2	2.7	0.6 ± 0.3					
32	1210	3.2 ± 0.4	2.5 ± 0.3	2.8	0.6 ± 0.5					
43	1812	4.5 ± 0.4	3.2 ± 0.3	3.5	0.8 ± 0.3					
55	2220	5.7 ± 0.4	5.0 ± 0.4	3.5	1.0 ± 0.3					





NO	ITE	М	PERI	FORMANCE	TEST	CONDITION						
1	Appea	rance	No Abnormal Exterior	Appearance	Through Microscope(×10)						
2	Insula Resist		10,000MΩ or 500MΩ·μF v Rated Voltage is below 10,000MΩ or 100MΩ·μF v	w 16V ;	Apply the Rated Voltage For 60 ~ 120 Sec.							
3	Withsta	•	No Dielectric Breakdov Mechanical Breakdown		Class : 300% of the Rated Voltage for 1~5 sec. Class :250% of the Rated Voltage for 1~5 sec. is applied with less than 50mA current							
					Capacitance	Frequency	Voltage					
		Class	Within the specifie	d tolerance	1,000 pF	1MHz ±1 0%						
	Capacita				>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms					
4	nce				Capacitance	Frequency	Voltage					
		Class	Within the specifi	ed tolerance	10 μF	1kHz ±1 0%	1.0±0.2Vrms					
					>10 µF	120Hz±20%	0.5±0.1 V rms					
			Capacitance 30pF:	Q 1,000	Capacitance	Frequency	Voltage					
5	Q	Class	< 30pF		1,000 pF	1MHz ±1 0%						
			(C	: Capacitance)	>1,000 pF	1kHz ±1 0%	0.5 ~ 5 Vrms					
			1. Characteristic : A()	X5R), B(X7R), X(X6S)	Capacitance	Frequency	Voltage					
				Rated Voltage	Spec	10 <i>μ</i> F	1kHz ±1 0%	1.0±0.2Vrms				
										25V	0.025 max	. 10,45
			16V	0.035 max								
			10V	0.05 max	1							
			6.3V	0.05 max/ 0.10max*1	*1. 0201 C 0.022uF, 0	402 C 0.22uF,	0603 C 2.2uF,					
			2. Characteristic : F(Y	,	N805 C 4.7uF, 1206 1812 C 47uF, 2220 All Low Profile Capa 7 *2 0603 C 0.47uF, 08	C 100uF, citors (P.16).) C 22uF,					
6	Tan	Class	Rated Voltage	Spec	*3. 0402 C 0.033uF, 06							
			50V	0.05 max, 0.07max*2	All 0805, 1206 size		F					
			35V	0.07 max 0.05 max/	*4 1210 C>6.8uF							
			25V	0.05 max/ 0.07 max*3/ 0.09max*4	*5 0402 C 0.22uF							
			16V	0.09 max/ 0.125max*5	*6 All 1812 size							
			10V	0.125 max/ 0.16max*6	1							
			6.3V	0.16max	1							





Ma									
NO	ITE	M		PERFOR	MANCE	_	TEST CONDITION		
							shall be measured by the steps		
			Characte	rictice	Temp. Coefficient	shown in the	following table.		
			Cilalacte	ilistics	(PPW)	Step	Temp.()		
			COC	3	0 ± 30	1	25 ± 2		
		Class	PH		-150 ± 60	2	Min. operating temp. ± 2		
			RH		-220 ± 60	3	25 ± 2		
			SH		-330 ± 60	4	Max. operating temp ± 2		
			TH		-470 ± 60	5	25 ± 2		
			UL		-750 ± 120	(1) Class			
			SL +350 ~ -1000		` ′	Coefficient shall be calculated from			
	Temperature					the formula a			
7	Characteristics of Capacitance						$nt = \frac{C2 - C1}{C1 \times T} \times 10^6 \text{ [ppm/]}$		
						C1; Capacita	ance at step 3		
					0	C2: Capacita	ance at 85		
			Characte	eristics	Capacitance Change with No Bias	T: 60 (=8	35 -25)		
		Class	A(X5 B(X7		±15%	(2) CLASS			
			X(Xe	SS)	±22%	Capacitance Change shall be calculated from			
			F(Y5	iV)	+22% ~ -82%	formula as be	elow.		
							C1 × 100(%)		
							ance at step 3		
							ance at step 2 or 4		
							* Pressure for 10±1 sec.		
						^ 200g.f for 0	0201 case size.		
8	Adhesive	Strength	No Indicati	on Of Peel	ling Shall Occur On The				
0	of Termi	ination	Terminal E	lectrode.		500g.f			
						Bending limit	: 1mm		
		Apperance	No mecha	nical dam	nage shall occur.	Test speed ;			
			Ch and	lo rioti	Consoitants Observe	-	t board at the limit point in 5 sec.,		
			Charact	eristics	Capacitance Change	Then measur	e capacitance.		
			Clas	ss I	Within ±5% or ± 0.5 pF whichever is larger		20 R=340*		
9	Bending			A (VED)		50			
	Strength	Capacitance		A(X5R)/ B(X7R)/ X(X6S)	Within ±12.5%	1	<u> </u>		
			Class II	(122)		45±1	Bending limit		
				F(Y5V)	Within ±30%	R=230_For	0201 Case size		





NO	I	ЕМ		PERF	ORMANCE		TEST CON	NDITION		
			More Than	n 95% of th	ne terminal surface is to	Solder	Sn-3Ag-0.5	Cu 63Sn-37Pb		
			be soldere	ed newly, So	metal part does not	Solder				
			come out	or dissolve		Temp.	245±5	235±5		
10	Solde	erability			//	Flux	R	МА Туре		
			-		/_// 	Dip Time	e 3±0.3 sec	5±0.5 sec.		
						Pre-heatir	ng at 80~120	for 10~30 sec.		
		Apperance	No mecha	anical dam	age shall occur.	Solder Tei	mperature: 270	±5		
			Charac	teristics	Capacitance Change	1	: 10±1 sec.			
					Within ±2.5% or			fully immersed and		
			Clas	ss	±0.25pF whichever is	preheated as below :				
		Capacitance			larger	STEP	TEMP.()	TIME(SEC.)		
				A(X5R)/ B(X7R)	Within ±7.5%	1	80~100	60		
			Class	X(X6S)	Within ±15%	2	150~180	60		
	Resistance to			F	Within ±20%	Leave the	canacitor in ar	phient condition for		
11	Soldering heat	oldering heat		nce 30pF	: Q 1000	Leave the capacitor in ambient condition for specified time* before measurement				
		Q		<30 pF	: Q 400+20×C	* 24 ± 2 hours (Class)				
		(Class)			(C: Capacitance)	48 ± 4	hours (Class)		
		Tan	Mithin the	a an a sifie d	initial value	1				
		(Class)	VVIIIIIII UIE	specified	Illitiai value					
		Insulation	Within the	e specified	initial value					
		Resistance		<u> </u>						
		Withstanding Voltage	Within the	e specified	initial value					
		vollage								
		Appearance	No mecha	anical dam	age shall occur.					
			Charact	teristics	Capacitance Change	-				
					Within ±2.5% or		citor shall be su	-		
			Clas	ss	±0.25pF whichever is		-	a total amplitude of		
		Capacitance			larger		anging frequenc to 10Hz In 1 m	ry from 10Hz to 55H nin		
		Capasitanics		A(X5R)/	Within ±5%	and back	10 10112 111 1 11			
12	Vibration		Class		Mish in 1400/	Repeat thi	s for 2hours ea	ach in 3 mutually		
-	Test					perpendicu	ılar directions			
		0		F(15V)	VVIIIIII ±20%	-				
		(Class)	Within the	e specified	initial value					
		Tan				1				
		(Class)	Within the	e specified	initial value					
		Insulation	NAPPOLIT OF							
		Resistance	Within the	e specified	initial value					
12	Test	Tan (Class) Insulation	Within the	Class $B(X7R)$ Within ±10% $X(X6S)$ Within ±20% Within the specified initial value Within the specified initial value				ich in 3 mutuany		





NO	ITE	М		PERFO	TEST CONDITION					
		Appearance	No mechanic	al damage sha	Il occur.	Temperature : 40±2				
			Charac	cteristics	Capacitance Change	Relative humidity: 90~95 %RH				
			Cla	ss	Within ±5.0% or ±0.5pF	Duration time : 500 +12/-0 hr.				
		Capacitance	Class	A(X5R)/ B(X7R)/ X(X6S)	whichever is larger Within ±12.5%	Leave the capacitor in ambient condition for specified time* before measurement.				
				F(Y5V)	Within ±30%	CLASS : 24±2 Hr.				
		Q	' '		350	CLASS : 48±4 Hr.				
4.0	Humidity	CLASS		•	275 + 2.5×C					
13	(Steady State)		Capacitance 1. Characteris	< 10pF : Q 2 stic : A(X5R), B(X7R)	200 + 10×C (C: Capacitance) 2. Characteristic : F(Y5V)					
			0.05max (16\	, ,	0.075max (25V and over)					
		Tan	0.075max (10	,	0.1max (16V, C<1.0μF)					
		CLASS	0.075max		0.125max(16V, C 1.0μF)					
		CLASS	(6.3V excep	t Table 1)	0.15max (10V)					
			0.125max*		0.195max (6.3V)					
			(refer to Tab	le 1)						
		Insulation Resistance	1,000 MΩ or	50MΩ·μF whichev	ver is smaller.					
		Appearance	No mechanic	al damage sha	ll occur.	Applied Voltage : rated voltage				
			Characteristics		Capacitance Change	Temperature: 40±2 Humidity::90~95%RH				
		Capacitance	Class		Within ±5.0% or ±0.5pF whichever is larger	Duration Time : 500 +12/-0 Hr. Charge/Discharge Current : 50mA max.				
				A(X5R)/ B(X7R)/ X(X6S)	Within ±12.5% Within ±12.5% Within ±30%	Perform the initial measurement according to Note1.				
			Class		Within ±30%					
				F(Y5V)	Within +30~ - 40% In case of Table 2 *	Perform the final measurement according to Note2.				
14	Moisture Resistance	Q (Class)	Capacitance Capacitance		200 200 + 10/3×C (C: Capacitance)					
			1. Characteri	stic : A(X5R), B(X7R)	2. Characteristic : F(Y5V)	_				
			0.05max (16\	/ and over)	0.075max (25V and over)					
			0.075max (10	OV)	0.1max (16V, C<1.0μF)					
		Tan	0.075max		0.125max(16V, C 1.0μF)					
		(Class)	(6.3V excep	t Table 1)	0.15max (10V)					
			0.125max*	ole 1)	0.195max (6.3V)					
			(refer to Table 1) X(X6S) 0.11max (6.3V and below)			-				
		Insulation Resistance	500 MΩ or 25	5MΩ·μF whicheve	r is smaller.					





NO	ITE	М		PER	FORMANCE		TEST CONDIT	ION	
		Appearance	No mechanio	cal damage	shall occur.	1	oltage: 200%* of the	=	
			Charact	eristics	Capacitance Change		re: max. operating t ime: 1000 +48/-0 Hi	•	
					Within ±3% or ±0.3pF,	Charge/Dis	A max.		
			Class	3	Whichever is larger	- * refer to table(3) : 150%/100% of the rate			
		Capacitance		A(X5R)/ B(X7R)	Within ±12.5%	voltage	• •		
			Class	X(X6S)	Within ±25%	Perform the	e initial measurement	according to	
				Class		Within ±30%	Note1 for	Class	
				F(Y5V)	Within +30~ - 40%				
					* In case of Table 2	Perform the	e final measurement	according to	
		Q	Capacitance	•		Note2.		· ·	
		(Class)		tance <30 p					
	High		Capacitance 1. Character		200 +10×C (C: Capacitance) 2), 2. Characteristic: F(Y5V)	-			
15	Temperature Resistance		1. Grandoton	B(X7R)					
	Resistance		0.05max		0.075max				
					(16V and over)		(25V and over)		
			0.075max (10V)		0.1max(16V, C<1.0μF)				
		Tan	0.075max		0.125max(16V, C 1.0μF)				
		(Class)	(6.3V except	ot Table 1)	0.15max (10V)				
			0.125max*		0.195max (6.3V)				
			refer to Ta	ble 1)					
			X(X6S) 0.11	max (6.3V a	nd below)				
		Insulation Resistance	1,000 MΩ or	50MΩ·μF Whio	chever is smaller.				
		Appearance	No mechanio	cal damage	shall occur.	Capacitor	shall be subjected	d to 5 cycles.	
		<u> </u>	Charact		Capacitance Change	Condition	for 1 cycle :		
			~		Within ±2.5% or ±0.25pF	Step	Temp.()	Time(min.)	
			Class	•	Whichever is larger	1	Min. operating	30	
		Capacitance		A(X5R)/	Within ±7.5%	2	temp.+0/-3	2~3	
	Temperature		Class	B(X7R)/ X(X6S)	Within ±15%	-	Max. operating	2~3	
16	Cycle			F(Y5V)	Within ±20%	3	temp.+3/-0	30	
		Q		1 (1-1)	1	4	25	2~3	
		(Class)	Within the s	pecified initia	al value	Leave the	e capacitor in amb	ient condition	
		Tan				+	ied time* before m		
		(Class)	Within the s	pecified initia	al value	* 24 ± 2 hours (Class) 48 ± 4 hours (Class)			
		Insulation	\\\/\!\	n a alfia el de lo	d value				
		Resistance	Within the s	peciriea initia	ıı value				





		Reco	ommended Sold	ering Method		
		Size	Temperature		Cond	ition
		inch (mm)	Characteristic	Capacitance	Flow	Reflow
		0201 (0603)	-	-	-	
		0402 (1005)				
			Class I	-		
		0603 (1608)	Class II	C < 1μF		
	Recommended		Class II	C 1μF	-	
		0805 (2012)	Class I	-		
18	Soldering Method		Class II	C < 4.7μF		
	By Size & Capacitance		Class II	C 4.7μF	-	
	by ones a supusitation		Array	-	-	
			Class I	-		
		1006 (2216)	Class II	C < 10μF		
		1206 (3216)	Class II	C 10μF	-	
			Array	-	-	
		1210 (3225)				
		1808 (4520)				
		1812 (4532)	-	-	-	
		2220 (5750)				

Note1. Initial Measurement For Class

Perform the heat treatment at 150 \pm +0/-10 for 1 hour. Then Leave the capacitor in ambient condition for 48±4 hours before measurement. Then perform the measurement.

Note2. Latter Measurement

1. CLASS

Leave the capacitor in ambient condition for 24±2 hours before measurement

Then perform the measurement.

2. Class

Perform the heat treatment at 150 \pm +0/-10 for 1 hour. Then Leave the capacitor in ambient condition for 48±4 hours before measurement. Then perform the measurement.

*Table1.

Tan 0.125max* 0201 C 0.022μF 0402 C 0.22μF 0603 C 2.2μF 0805 C 4.7μF Class 1206 C 10.0μF A(X5R), 1210 C 22.0μF B(X7R) 1812 C 47.0μF 2220 C 100.0μF All Low Profile Capacitors (P.16).

*Table2.

perature Resistance test
+30~ - 40%
0402 C 0.47μF
0603 C 2.2μF
0805 C 4.7μF
1206 C 10.0μF
1210 C 22.0μF
1812 C 47.0μF
2220 C 100.0μF

*Table3.

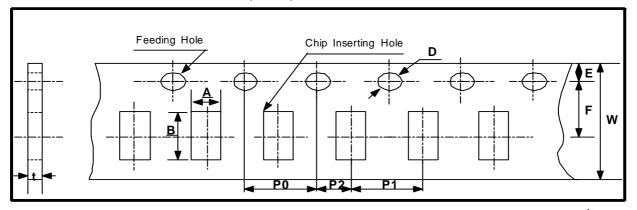
	High Temperature Resi	stance test		
Applied Voltage	100% of the rated voltage	150% of the rated voltage		
Class A(X5R), B(X7R), X(X6S), F(Y5V)	0201 C 0.1 μF 0402 C 1.0 μF 0603 C 4.7 μF 0805 C 22.0 μF 1206 C 47.0 μF 1210 C 100.0 μF All Low Profile Capacitors (P.16).	0201 C 0.022 μF 0402 C 0.47 μF 0603 C 2.2 μF 0805 C 4.7 μF 1206 C 10.0 μF 1210 C 22.0 μF 1812 C 47.0 μF 2220 C 100.0 μF		





PACKAGING

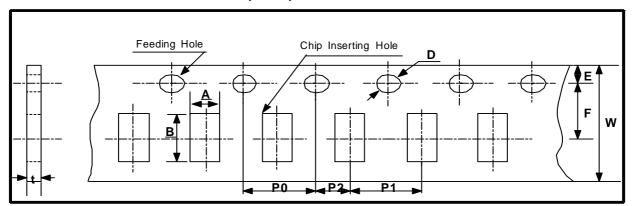
CARDBOARD PAPER TAPE (4mm)



unit : mm

	mbol ype	Α	В	w	F	E	P1	P2	P0	D	t
D i m	0603 (1608)	1.1 ±0.2	1.9 ±0.2								
e n s	0805 (2012)	1.6 ±0.2	2.4 ±0.2	8.0 ±0.3	3.5 ±0.05	1.75 ±0.1	4.0 ±0.1	2.0 ±0.05	4.0 ±0.1	1.5 +0.1/-0	1.1 Below
i o n	1206 (3216)	2.0 ±0.2	3.6 ±0.2								

CARDBOARD PAPER TAPE (2mm)



unit: mm

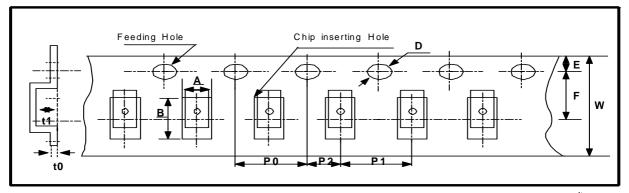
Symbol Type		Α	В	w	F	E	P1	P2	P0	D	t
D i m e	0201 (0603)	0.38 ±0.03	0.68 ±0.03	8.0	3.5	1.75	2.0	2.0	4.0	1.5	0.37 ±0.03
n s i o n	0402 (1005)	0.62 ±0.04	1.12 ±0.04	±0.3	±0.05	±0.1	±0.05	±0.05	±0.1	+0.1/-0.03	0.6 ±0.05





PACKAGING

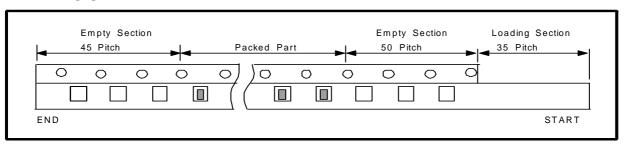
EMBOSSED PLASTIC TAPE



unit: mm

	m bol ype	Α	В	w	F	E	P1	P 2	P 0	D	t1	t0
	0805 (2012)	1.45 ±0.2	2.3 ±0.2									
P	1206 (3216)	1.9 ±0.2	3.5 ±0.2	8.0 ±0.3	3.5 ±0.05		4.0 ±0.1				2.5 max	
m e	1210 (3225)	2.9 ±0.2	3.7 ±0.2			1.75		2.0	4.0	1.5 +0.1/-0		0.6
n s i	1808 (4520)	2.3 ±0.2	4.9 ±0.2			±0.1		±0.05	±0.1	+0.1/-0		Below
o n	1812 (4532)	3.6 ±0.2	4.9 ±0.2	12.0 ±0.3	5.60 ±0.05		8.0 ±0.1				3.8 max	
	2220 (5750)	5.5 ±0.2	6.2 ±0.2									

TAPING SIZE



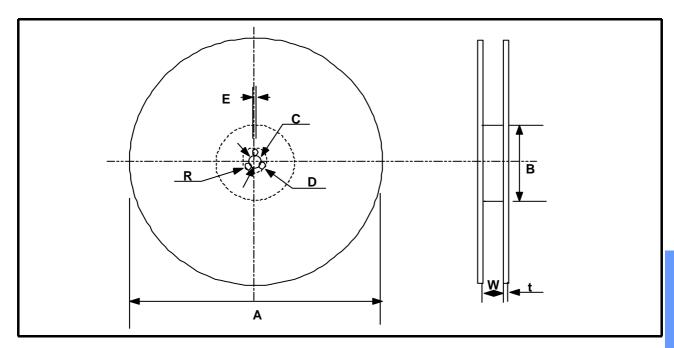
Type	Symbol	Size	Cardboard Paper Tape	Symbol	Size	Embossed Plastic Tape
		0201(0603) 10,000		All Size 3216 1210(3225),1808(4520) (t 1.6mm)	2,000	
7" Reel	С	0402(1005)	10,000	E	1210(3225)(t 2.0mm)	1,000
		OTHERS	4,000		1808(4520)(t 2.0mm)	1,000
10" Reel	0	-	10,000	-	-	-
	D	0402(1005)	50,000		All Size 3216 1210(3225),1808(4520) (t<1.6mm)	10,000
		OTHERS	10,000		1210(3225)(1.6 t<2.0mm) 1206(3216)(1.6 t)	8,000
13" Reel		0603(1608)	10,000 or 15,000	F	1210(3225),1808(4520) (t 2.0mm)	4,000
	L	L 0805(2012) 15,000 or (t 0.85mm) 10,000(Option)		1812(4532)(t 2.0mm)	4,000	
		1206(3216) (t 0.85mm)	10,000		1812(4532)(t>2.0mm) 5750(2220)	2,000





PACKAGING

REEL DIMENSION



unit : mm

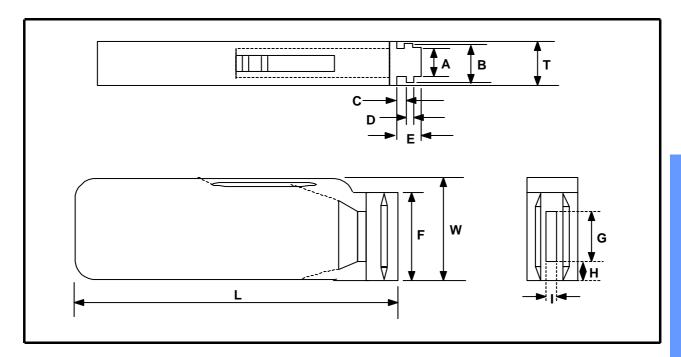
Symbol	Α	В	С	D	E	W	t	R
7" Reel	180+0/ -3	60+1/ -3	40.00	25 . 0 5	20.05	0 . 4 5	1.2±0.2	4.0
13" Reel	330±2.0	80+1/ -3	13±0.3	25 ± 0.5	2.0±0.5	9±1.5	2.2±0.2	1.0





BULK CASE PACKAGING

- Bulk case packaging can reduce the stock space and transportation costs.
- The bulk feeding system can increase the productivity.
- It can eliminate the components loss.



unit: mm

Symbol	Α	В	Т	С	D	E
Dimension	6.8 ± 0.1	8.8 ± 0.1	12±0.1	1.5+0.1/-0	2+0/-0.1	3.0+0.2/-0

Symbol	F	W	G	Н	L	I
Dimension	31.5+0.2/-0	36+0/-0.2	19±0.35	7±0.35	110±0.7	5 ± 0.35

QUANTITY OF BULK CASE PACKAGING

unit: pcs

Ci	0402(4005)	0002(4000)	0805(2012)	
Size	0402(1005)	0603(1608)	T=0.65mm	T=0.85mm
Quantity	50,000	10,000 or 15,000	10,000	5,000 or 10,000

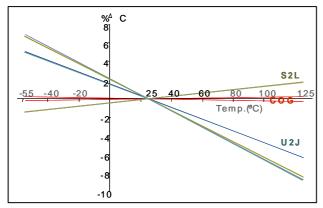


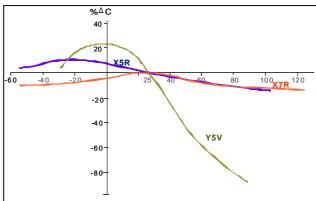


APPLICATION MANUAL

ELECTRICAL CHARACTERISTICS

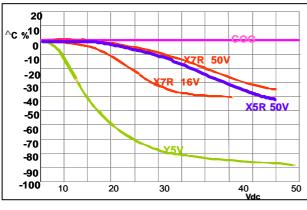
CAPACITANCE - TEMPERATURE CHARACTERISTICS



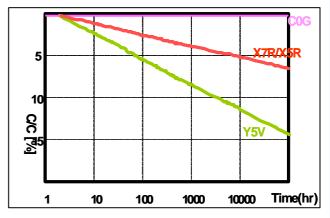


CAPACITANCE - DC VOLTAGE CHARACTERISTICS

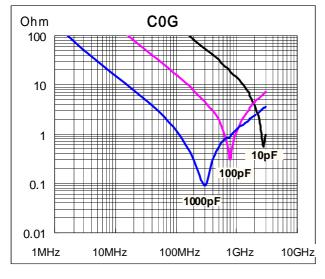
CAPACITANCE - DC VOLTAGE CHARACTERISTICS

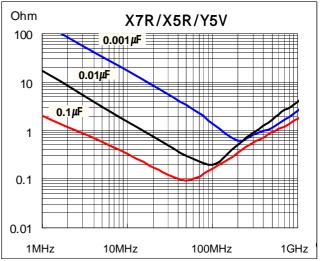


CAPACITANCE CHANGE - AGING



IMPEDANCE - FREQUENCY CHARACTERISTICS









STORAGE CONDITION

Storage Environment

The electrical characteristics of MLCCs were degraded by the environment of high temperature or humidity. Therefore, the MLCCs shall be stored in the ambient temperature and the relative humidity of less than 40 and 70%, respectively.

Guaranteed storage period is within 6 months from the outgoing date of delivery.

Corrosive Gases

Since the solderability of the end termination in MLCC was degraded by a chemical atmosphere such as chlorine, acid or sulfide gases, MLCCs must be avoid from these gases.

Temperature Fluctuations

Since dew condensation may occur by the differences in temperature when the MLCCs are taken out of storage, it is important to maintain the temperature-controlled environment.

DESIGN OF LAND PATTERN

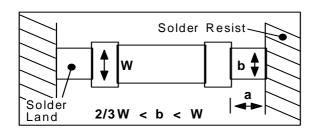
When designing printed circuit boards, the shape and size of the lands must allow for the proper amount of solder on the capacitor.

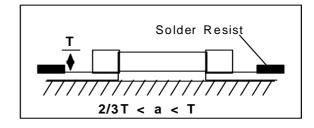
The amount of solder at the end terminations has a direct effect on the crack.

The crack in MLCC will be easily occurred by the tensile stress which was due to too much amount of solder. In contrast, if too little solder is applied, the termination strength will be insufficiently.

Use the following illustrations as guidelines for proper land design.

Recommendation of Land Shape and Size.









ADHESIVES

When flow soldering the MLCCs, apply the adhesive in accordance with the following conditions.

Requirements for Adhesives

They must have enough adhesion, so that, the chips will not fall off or move during the handling of the circuit board.

They must maintain their adhesive strength when exposed to soldering temperature.

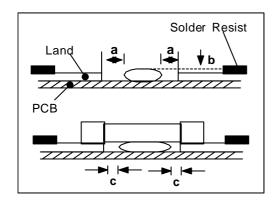
They should not spread or run when applied to the circuit board.

They should harden quickly. They should not corrode the circuit board or chip material.

They should be a good insulator. They should be non-toxic, and not produce harmful gases, nor be harmful when touched.

Application Method

It is important to use the proper amount of adhesive. Too little and much adhesive will cause poor adhesion and overflow into the land, respectively.



		unit : mm
Туре	21	31
а	0.2 min	0.2 min
b	70~100μm	70~100μm
С	> 0	> 0

Adhesive hardening Characteristics

To prevent oxidation of the terminations, the adhesive must harden at 160 or less, within 2 minutes or less.

MOUNTING

Mounting Head Pressure

Excessive pressure will cause crack to MLCCs. The pressure of nozzle will be 300g maximum during mounting.

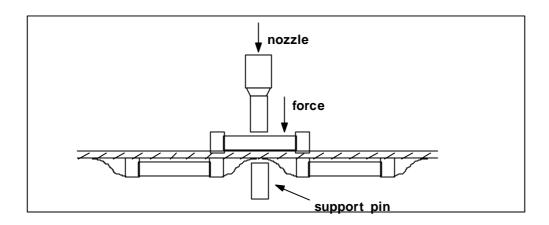




Bending Stress

When double-sided circuit boards are used, MLCCs first are mounted and soldered onto one side of the board. When the MLCCs are mounted onto the other side,

it is important to support the board as shown in the illustration. If the circuit board is not supported, the crack occur to the ready-installed MLCCs by the bending stress.



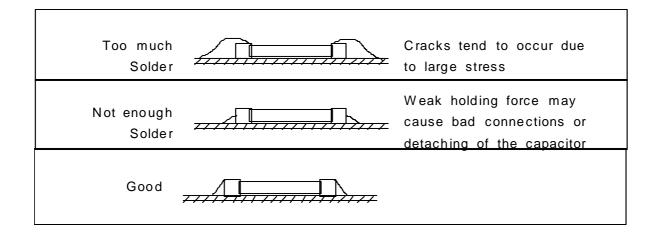
Manual Soldering

Manual soldering can pose a great risk of creating thermal cracks in chip capacitors.

The hot soldering iron tip comes into direct contact with the end terminations, and operator's carelessness may cause the tip of the soldering iron to come into direct contact with the ceramic body of the capacitor.

Therefore the soldering iron must be handled carefully, and close attention must be paid to the selection of the soldering iron tip and to temperature control of the tip.

Amount of Solder







Cooling

Natural cooling using air is recommended. If the chips are dipped into solvent for cleaning, the temperature difference(T) must be less than 100

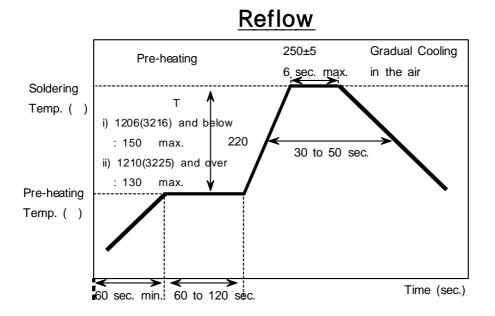
Cleaning

If rosin flux is used, cleaning usually is unnecessary. When strongly activated flux is used, chlorine in the flux may dissolve into some types of cleaning fluids, thereby affecting the chip capacitors. This means that the cleaning fluid must be carefully selected, and should always be new.

Notes for Separating Multiple, Shared PC Boards.

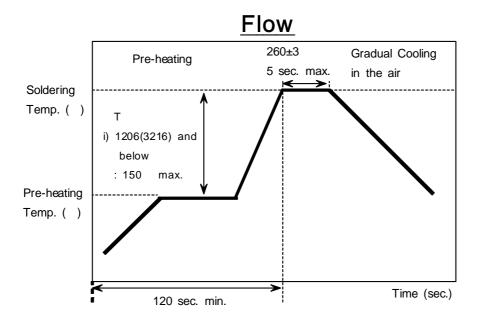
A multi-PC board is separated into many individual circuit boards after soldering has been completed. If the board is bent or distorted at the time of separation, cracks may occur in the chip capacitors. Carefully choose a separation method that minimizes the bending often circuit board.

Recommended Soldering Profile









Soldering Iron

Variation of Temp.	Soldering	Pre-heating	Soldering	Cooling
	Temp ()	Time (Sec)	Time(Sec)	Time(Sec)
T 130	300±10 max	60	4	-

Condition of Iron facilities				
Wattage Tip Diameter		Soldering Time		
20W Max	3mm Max	4 Sec Max		

^{*} Caution - Iron Tip Should Not Contact With Ceramic Body Directly.

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Other Similar products are found below:

D55342E07B523DR-T/R NCA1206X7R103K50TRPF NCA1206X7R104K16TRPF NIN-FB39IJTRF NIN-FC2R7JTRF
NMC0402NPO220J50TRPF NMC0402X5R105K6.3TRPF NMC0402X5R224K6.3TRPF NMC0402X7R103J25TRPF
NMC0402X7R153K16TRPF NMC0603NPO20JJ50TRPF NMC0603NPO330G50TRPF NMC0603NPO331F50TRPF
NMC0603X5R475M6.3TRPF NMC0805NPO220JJ00TRPF NMC0805NPO270J50TRPF NMC0805NPO681F50TRPF
NMC0805NPO820J50TRPF NMC0805X7R224K25TRPF NMC1206NPO150J50TRPF NMC1206X7R106K10TRPLPF
NMC1210Y5V105Z50TRPLPF NMC-L0402NPO7R0C50TRPF NMC-L0603NPO2R2B50TRPF NMC-Q0402NPO8R2D200TRPF
C1206C101J1GAC C1608C0G2A221J C1608X7R1E334K C2012C0G2A472J 2220J2K00562KXT KHC201E225M76N0T00
1812J2K00332KXT CDR14BP471CJUR CDR31BX103AKWR CDR33BX683AKUS CGA2B2C0G1H010C CGA2B2C0G1H040C
CGA2B2C0G1H050C CGA2B2C0G1H060D CGA2B2C0G1H070D CGA2B2C0G1H120J CGA2B2C0G1H151J CGA2B2C0G1H1R5C
CGA2B2C0G1H2R2C CGA2B2C0G1H390J CGA2B2C0G1H391J CGA2B2C0G1H3R3C CGA2B2C0G1H680J CGA2B2C0G1H6R8D
CGA2B2C0G1H820J